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Substitute for Form 1449A/PTO	Complete if Known		
	Application Number	10/635,344	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Filing Date	August 6, 2003	
0.1	First Named Inventor	Alan E. Delahoy et al.	
Be and A	Group Art Unit	1753	
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SNOT PERSON OF 2	Attorney Docket Number	ENPI 0101 PUS	

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Examiner Cite Initials No.1		U.S. PATENT D	OCUMENT Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Clusi Subclus Pages, Columns, lines, Where Relevant Passages or Relevant Figures Appear		
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Examiner Signature Date Considered April 14 2005

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not

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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here it English language Translation is attached.

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Substitute for For	m 1449B/PTO		Complete if Known					
			Application Number	10/635,344				
		SCLOSURE APPLICANT	Filing Date	August 6, 2003				
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